



## Description

The FDD3706 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge . The complementary MOSFETs may be used to form a level shifted high side switch, and for a host of other applications

## General Features

$V_{DS} = 20V, I_D = 40A$   
 $R_{DS(ON)} < 9 m\Omega @ V_{GS}=4.5V$

High power and current handing capability  
Lead free product is acquired  
Surface mount package

## Application

- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply

## Package Marking and Ordering Information

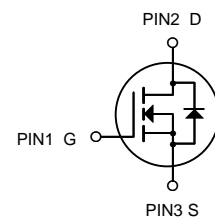
Product ID	Pack	Brand	Qty(PCS)
FDD3706	TO-252-2L	HXY MOSFET	2500

## Absolute Maximum Ratings@ $T_J=25^\circ C$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	20	V
VGS	Gate-Source Voltage	$\pm 12$	V
$I_D @ T_C=25^\circ C$	Drain Current, $V_{GS} @ 4.5V$	40	A
$I_D @ T_C=100^\circ C$	Drain Current, $V_{GS} @ 4.5V$	25	A
IDM	Pulsed Drain Current <sup>1</sup>	80	A
$P_D @ T_C=25^\circ C$	Total Power Dissipation	15.6	W
$P_D @ T_A=25^\circ C$	Total Power Dissipation <sup>3</sup>	5	W
EAS	Single Pulse Avalanche Energy <sup>4</sup>	150	mJ
TSTG	Storage Temperature Range	-55 to 150	$^\circ C$
$T_J$	Operating Junction Temperature Range	-55 to 150	$^\circ C$
Rthj-c	Maximum Thermal Resistance, Junction-case	8	$^\circ C/W$
Rthj-a	Maximum Thermal Resistance, Junction-ambient <sup>3</sup>	25	$^\circ C/W$



TO-252-2L



N-Channel MOSFET



**Electrical Characteristics@T<sub>j</sub>=25°C(unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	20	-	-	V
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =20A	-	7.5	9	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =12A	-	9.1	12	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	0.5	-	0.9	V
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =20A	-	50	-	S
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =16V, V <sub>GS</sub> =0V	-	-	10	uA
I <sub>GSS</sub>	Gate-Source Leakage	V <sub>GS</sub> =+12V, V <sub>DS</sub> =0V	-	-	+100	nA
Q <sub>g</sub>	Total Gate Charge	I <sub>D</sub> =20A	-	16	25.6	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =10V	-	3	-	nC
Q <sub>gd</sub>	Gate-Drain ("Miller") Charge	V <sub>GS</sub> =4.5V	-	4.5	-	nC
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>DS</sub> =10V	-	10	-	ns
t <sub>r</sub>	Rise Time	I <sub>D</sub> =1A	-	13	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time	R <sub>G</sub> =3.3Ω	-	28	-	ns
t <sub>f</sub>	Fall Time	V <sub>GS</sub> =5V	-	7	-	ns
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V	-	1400	2240	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =10V	-	170	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f=1.0MHz	-	135	-	pF
R <sub>g</sub>	Gate Resistance	f=1.0MHz	-	1	2	Ω
V <sub>SD</sub>	Forward On Voltage <sup>2</sup>	I <sub>S</sub> =20A, V <sub>GS</sub> =0V	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> =12A, V <sub>GS</sub> =0V,	-	8.5	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI/dt=100A/μs	-	2.5	-	nC

**Notes:**

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board, t ≤10sec ; 60 °C/W at steady state.
- 4.Starting T<sub>j</sub>=25°C , V<sub>DD</sub>=20V , L=0.1mH , R<sub>G</sub>=25Ω, V<sub>GS</sub>=10V



### Typical Characteristics

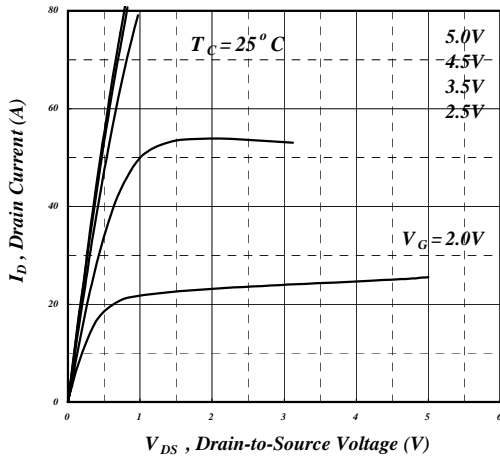


Fig 1. Typical Output Characteristics

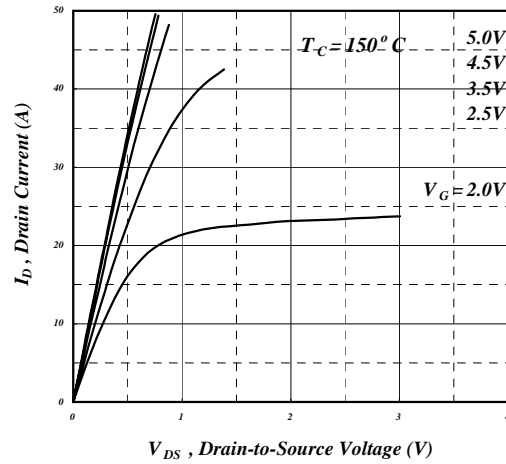


Fig 2. Typical Output Characteristics

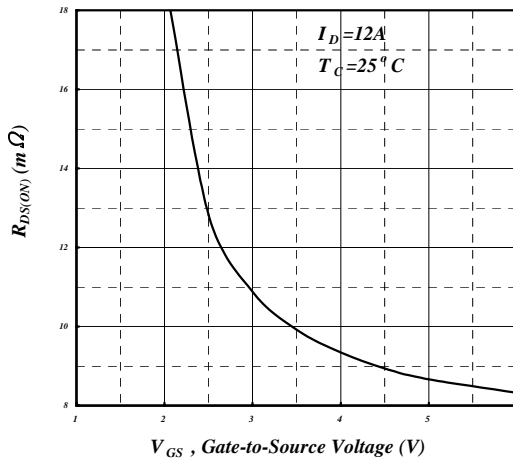


Fig 3. On-Resistance v.s. Gate Voltage

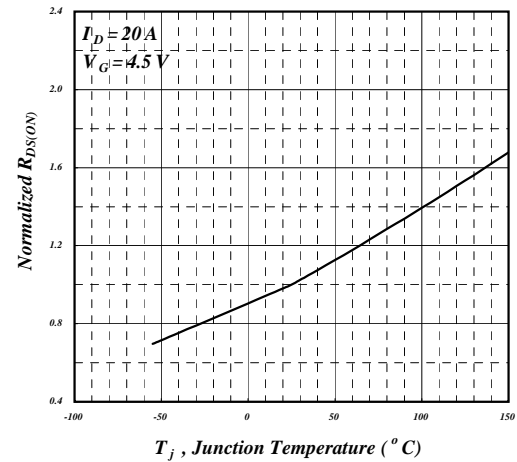


Fig 4. Normalized On-Resistance v.s. Junction Temperature

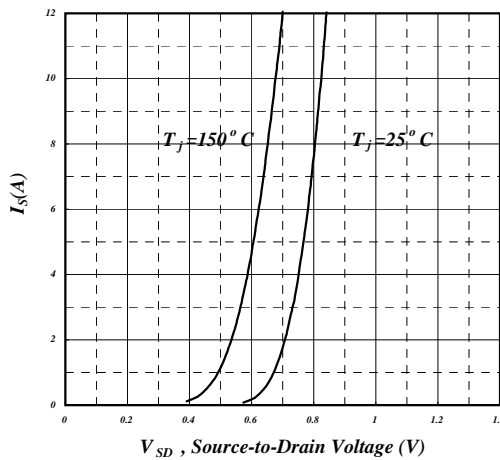


Fig 5. Forward Characteristic of Reverse Diode

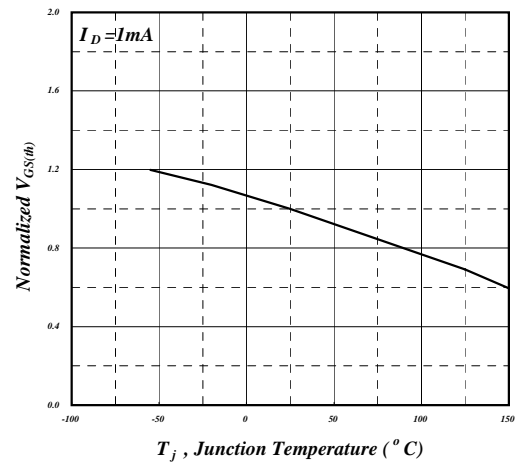


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

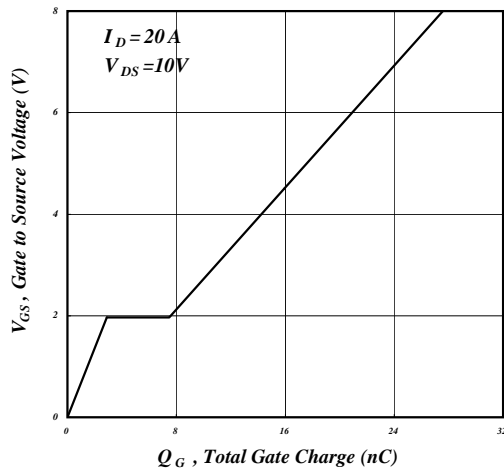


Fig 7. Gate Charge Characteristics

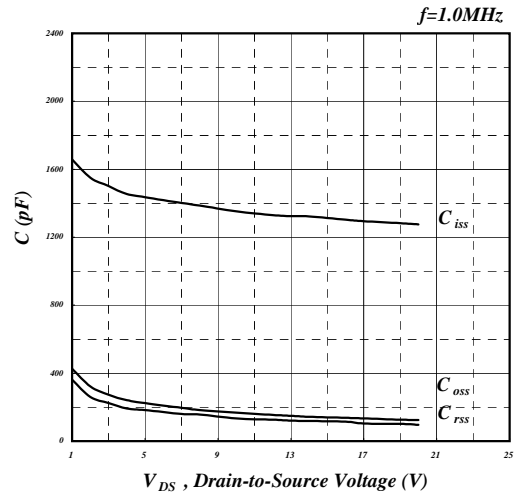


Fig 8. Typical Capacitance Characteristics

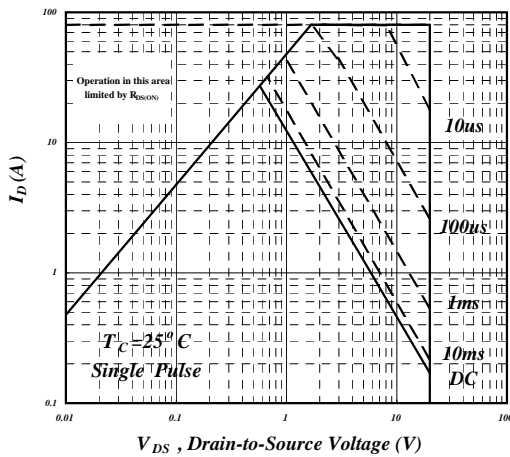


Fig 9. Maximum Safe Operating Area

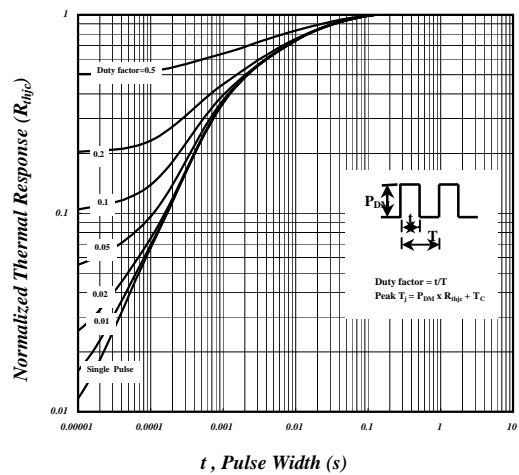


Fig 10. Effective Transient Thermal Impedance

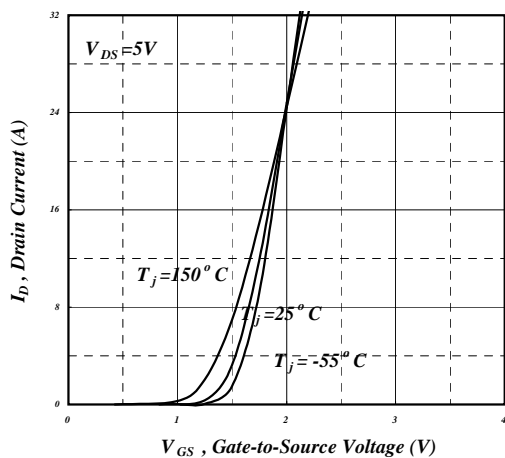


Fig 11. Transfer Characteristics

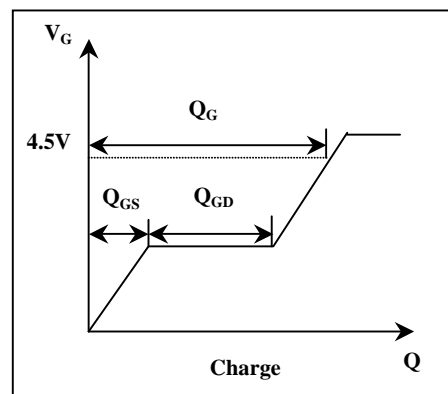


Fig 12. Gate Charge Waveform

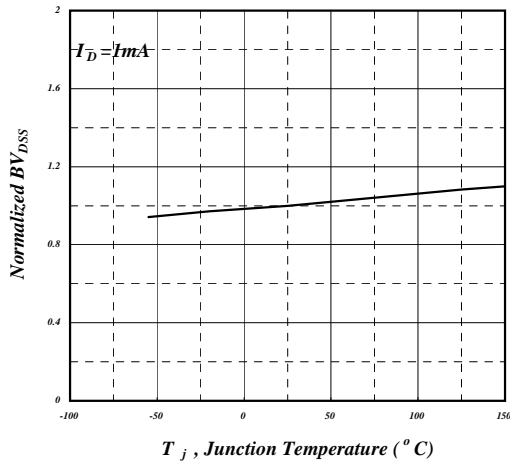


Fig 13. Normalized  $BV_{DSS}$  v.s. Junction Temperature

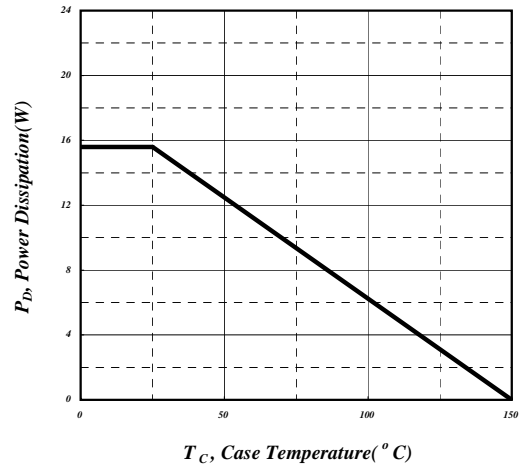


Fig 14. Total Power Dissipation

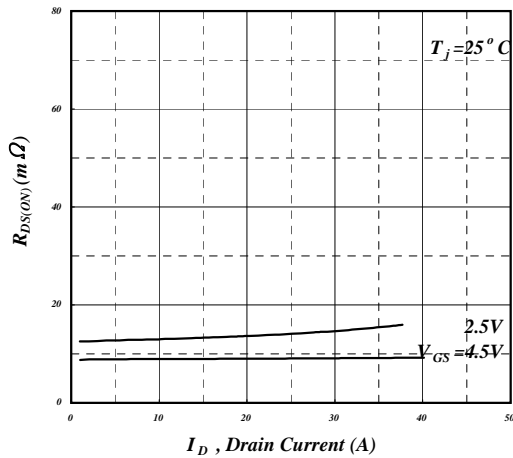


Fig 15. Typ. Drain-Source on State Resistance





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